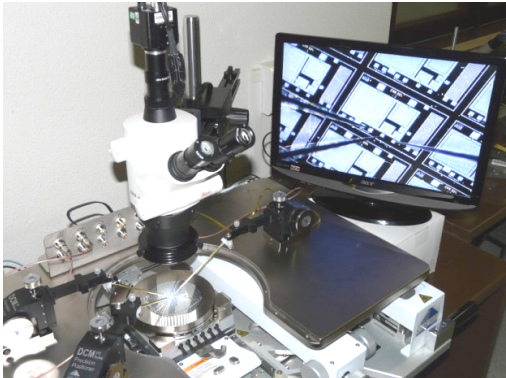

	<p>RF DEVICES LABORATORY</p>
<p>Description</p>	
<p>The laboratory of RF devices is dedicated to the characterization of semiconductor materials and sub-micrometer devices up to microwave frequencies. Our tools allow performing several kinds of on-wafer measurements from DC and pulsed characterization, to RF and electronic noise (up to 43.5 GHz).</p>	
<p>Equipment</p>	
<p>Cascade M150 probe station</p>	
<p>Keithley 4200-SCS parameter analyzer with the ultrafast I-V module Keithley 4225 allowing to perform pulsed measurements with pulse widths as narrow as 70 ns</p>	

Tektronix RSA5126A Real Time Signal Analyzer
1 Hz-26.5 GHz (with 110 MHz acquisition BW)



VNA Agilent N5244A PNA-X with low noise
receivers (option 029) for RF and noise
characterization up to 43.5 GHz

